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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Application of: Conant et al.

Confirmation No.: 1213

SEP 29 2003

Serial No.: 10/076.296

Art Unit: 1765

TC 1700

Filed: February 13, 2002

Examiner: ALANKO, ANITA KAREN

For: STAGGARD TORSIONAL  
ELECTROSTACTIC COMBDRIVE  
AND METHOD OF FORMING  
SAME

Attorney Docket No.: 9840-0068-999

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure provisions of 37 C.F.R. §1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the application.

1. Enclosures accompanying this Information Disclosure Statement are:

- 1a.  A list of all patents, publications, applications, or other information submitted for consideration by the office.
  - 1b. A legible copy of :
    - Each U.S. patent application publication and U.S. and foreign patent;
    - Each publication or that portion which caused it to be listed on the PTO-1449;
    - For each cited pending U.S. application, the application specification including the claims, and any drawing of the application, or portion of the application which caused it to be listed on the PTO-1449 including any claims directed to that portion;
    - all other information or portion which caused it to be listed on the PTO-1449.
  - 1c.  An English language copy of search report(s) from a counterpart foreign application or PCT International Search Report.
  - 1d.  Explanations of relevancy (ATTACHMENT 1(d), hereto) or English language abstracts of the non-English language publications.
2.  This Information Disclosure Statement is filed under 37 C.F.R. §1.97(b):  
 Within three months of the filing date of a national application other than a continued prosecution application under §1.53(d);



- Within three months of the date of entry of the national stage as set forth in §1.491 in an international application;
- Before the mailing of the first Office action on the merits;
- Before the mailing of a first Office action after the filing of a request for continued examination under §1.114.

3.  This Information Disclosure Statement is filed under 37 C.F.R. §1.97(c) after the period specified in 37 C.F.R. §1.97(b), but before the mailing date of any of a final action under 37 C.F.R. §1.113, a notice of allowance under 37 C.F.R. §1.311 or an action that otherwise closes prosecution in the application.

*(Check either Item 3a or 3b)*

- 3a.  The Certification Statement in Item 5 below is applicable. Accordingly, no fee is required.
- 3b.  The \$180.00 fee set forth in 37 C.F.R. §1.17(p) in accordance with 37 C.F.R. §1.97(c) is:  
 enclosed  
 to be charged to Pennie & Edmonds LLP Deposit Account No. 16-1150.

*(Item 3b to be checked if any reference known for more than 3 months)*

4.  This Information Disclosure Statement is filed under 37 C.F.R. §1.97(d) after the period specified in 37 C.F.R. §1.97(c), but on or before the date of payment of the issue fee.

The \$180.00 fee set forth in 37 C.F.R. §1.17(p) is:  
 enclosed.  
 to be charged to Pennie & Edmonds LLP Deposit Account No. 16-1150.

The Certification Statement in Item 5 below is applicable.

5.  Certification Statement (applicable if Item 3a or Item 4 is checked)

*(Check either Item 5a or 5b)*

- 5a.  In accordance with 37 C.F.R. §1.97(e)(1), it is certified that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.
- 5b.  Each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart application, and the communication was not **received** by any individual designated in 37 C.F.R. §1.56(c) more than thirty days prior to the filing of this information disclosure statement.
- 5c.  Pursuant to 37 C.F.R. §1.704(d), each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart application, and the communication was not **received** by any individual designated in 37 C.F.R. §1.56(c) more than thirty days prior to the filing of this information disclosure statement.



- This application is a divisional application under 37 C.F.R. §1.60 or §1.53(b) or (d).

*(Check appropriate Items 6a, 6b and/or 6c)*

- 6a.  A Petition to Withdraw from issue under 37 C.F.R. §1.313(b)(5) is concurrently filed herewith.
- 6b.  Copies of publications listed on Form PTO-1449 from prior application Serial No. 09/584,835, filed on May 31, 2000, of which this application claims priority under 35 U.S.C. §120, are not being submitted pursuant to 37 C.F.R. §1.98(d).
- 6c.  Copies of the publications listed on Form PTO-1449 were not previously cited in prior application Serial No. , filed on , and are provided herewith.
7.  This is a Supplemental Information Disclosure Statement. (Check Item 7a)
- 7a.  This Supplemental Information Disclosure Statement under 37 C.F.R. §1.97(f) supplements the Information Disclosure Statement filed on . A bona fide attempt was made to comply with 37 C.F.R. §1.98, but inadvertent omissions were made. These omissions have been corrected herein. Accordingly, additional time is requested so that this Supplemental Information Disclosure Statement can be considered as if properly filed on .
8.  In accordance with 37 C.F.R. §1.98, a concise explanation of what is presently understood to be the relevance of each non-English language publication is:

*(Check Item 8a, 8b, or 8c)*

- 8a.  satisfied because all non-English language publications were cited on the enclosed English language copy of the PCT International Search Report or the search report from a counterpart foreign application indicating the degree of relevance found by the foreign office.
- 8b.  set forth in the application.
- 8c.  enclosed as an attachment hereto.
9.  The Commissioner is authorized to charge any additional fee required or credit any overpayment for this Information Disclosure Statement and/or Petition to Pennie & Edmonds LLP Deposit Account No. 16-1150.
10.  No admission is made that the information cited in this Statement is, or is considered to be, material to patentability nor a representation that a search has been made (other than a search report of a foreign counterpart application or PCT International Search Report if submitted herewith). 37 C.F.R. §§1.97(g) and (h).

Respectfully submitted,

Gary S. Williams  
PENNIE & EDMONDS LLP  
3300 Hillview Avenue  
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(650) 493-4935

31,066

(Reg. No.)

Date: September 19, 2003



**LIST OF REFERENCES CITED BY APPLICANT**  
(Use several sheets if necessary)

ATTY DOCKET NO 9840-0068-999	APPLICATION NO 10,076,296
APPLICANT Conant et al.	
FILING DATE February 13, 2002	GROUP 1765

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SEP 25 2003  
TC 176

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	YES	NO

**OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)**

	Conant et al. "Cyclic Fatigue Testing of Surface-Micromachined Thermal Actuators", 1998 ASME International Mechanical Engineering Congress and Exposition, Nov. 15-20, 1998, Anaheim, CA DSC-Vol. 66, pp. 273-277
	Cotton et al., "Wide-angle geocornal telescope: a He-II 304-A plasmaspheric imager", Optical Engineering, December 1993, Vol. 32 No. 12, pages 3170-3173
	Hart et al., "Stroboscopic phase-shifting interferometry for dynamic characterization of optical MEMS", 18th Congress of the International Commission for Optics, ICO XVIII August 2-6, 1999, San Francisco, CA USA, Optics for the Next Millennium, Technical Digest SPIE Volume 3749, pgs 468-469
	Hoon et al., "A Model for SIMOX Buried-Oxide High-Field Conduction", IEEE Transactions on Electron Devices, Vol. 43, No. 11, November 1996
	Hyodo et al., "An HDR System Hydraulics Model and Detailed Analysis of the 1991 Circulation Test at the Hijiori HDR Site, Japan", Geothermal Resources Council Transactions, Vol. 198, October 1995, pgs 263-268
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	Wright et al., "Hydraulic Fracture Orientation and Production/Injection Induced Reservoir Stress Changes in Diatomite Waterfloods", Society of Petroleum Engineers, pages 139-151
	Wright et al., "Reorientation of propped fracture treatments", Eurock '97 © 1994 Balkema, Rotterdam, ISBN 90 5410 502 X, pages 417-424
	Yap et al., "Conduction Mechanisms Through Simox Buried Oxide", in Proceedings of 1993 IEEE International SOI Conference, Palm Springs, CA, USA, October 5-7, 1993, pp. 32-33
	Yap et al., "A Model for High-Field Conduction In Simox Buried Oxides", in Proceedings of 1994 IEEE International SOI Conference, Nantucket, MA, USA, October 3-6, 1994, pp. 93-94
	Yao and MacDonald, "Single Crystal Silicon Supported Thin Film Micromirrors for Optical Applications", Opt. Eng., 36(5):1408-1413, May 1997
	Yeh et al., "Integrated Polysilicon and DRIE Bulk Silicon Micromachining for an Electrostatic Torsional Actuator", J. Microelectromechanical Systems, 8(4):456-465, Dec. 1999
	Yeh et al. "Mechanical Digital-To-Analog Converters", proc. Transducers '99, Sendai, Japan, June 1999, pp. 998-1001
	Yoon et al. "Use of High-Field Electrical Testing for SIMOX BOX Metrology", in Proceedings of 1995 IEEE International SOI Conference, Tucson, AZ, USA, October 3-5, 1995, pp. 146-147

EXAMINER	DATE CONSIDERED

\*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.